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"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	50MHz
Connectivity	I²C, SMBus, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	13
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	2.25K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 11x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	20-WFQFN Exposed Pad
Supplier Device Package	20-QFN (3x3)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8ub10f16g-c-qfn20r

1. Feature List

The EFM8UB1 highlighted features are listed below.

- Core:
  - Pipelined CIP-51 Core
  - Fully compatible with standard 8051 instruction set
  - 70% of instructions execute in 1-2 clock cycles
  - 50 MHz maximum operating frequency
- Memory:
  - Up to 16 KB flash memory, in-system re-programmable from firmware, including 1 KB of 64-byte sectors and 15 KB of 512-byte sectors.
  - Up to 2304 bytes RAM (including 256 bytes standard 8051 RAM, 1024 bytes on-chip XRAM, and 1024 bytes of USB buffer)
- Power:
  - 5 V-input LDO regulator for direct connection to USB supply
  - Internal LDO regulator for CPU core voltage
  - Power-on reset circuit and brownout detectors
- I/O: Up to 22 total multifunction I/O pins:
  - All pins 5 V tolerant under bias
  - Flexible peripheral crossbar for peripheral routing
  - 5 mA source, 12.5 mA sink allows direct drive of LEDs
- Clock Sources:
  - Internal 48 MHz oscillator with accuracy of ±1.5% standalone and ±0.25% using USB clock recovery
  - Internal 24.5 MHz oscillator with ±2% accuracy
  - Internal 80 kHz low-frequency oscillator
  - External CMOS clock option
- Timers/Counters and PWM:
  - 3-channel Programmable Counter Array (PCA) supporting PWM, capture/compare, and frequency output modes
  - 5 x 16-bit general-purpose timers
  - Independent watchdog timer, clocked from the low frequency oscillator
- Communications and Digital Peripherals:
  - USB 2.0-compliant full speed with integrated low-power transceiver, 4 bidirectional endpoints, and dedicated 1 KB buffer
  - 2 x UART, up to 3 Mbaud
  - SPI™ Master / Slave, up to 12 Mbps
  - SMBus™/I2C™ Master / Slave, up to 400 kbps
  - I^2C High-Speed Slave, up to 3.4 Mbps
  - 16-bit CRC unit, supporting automatic CRC of flash at 256-byte boundaries
- Analog:
  - 12-Bit Analog-to-Digital Converter (ADC)
  - 2 x Low-current analog comparators with adjustable reference
- On-Chip, Non-Intrusive Debugging
  - Full memory and register inspection
  - Four hardware breakpoints, single-stepping
- Pre-loaded USB bootloader
- Temperature range -40 to 85 ºC
- Single power supply of 2.2 to 3.6 V or 3.0 to 5.25 V
- QSOP24, QFN28, and QFN20 packages

With on-chip power-on reset, voltage supply monitor, watchdog timer, and clock oscillator, the EFM8UB1 devices are truly standalone system-on-a-chip solutions. The flash memory is reprogrammable in-circuit, providing nonvolatile data storage and allowing field upgrades of the firmware. The on-chip debugging interface (C2) allows non-intrusive (uses no on-chip resources), full speed, in-circuit debugging using the production MCU installed in the final application. This debug logic supports inspection and modification of memory and registers, setting breakpoints, single stepping, and run and halt commands. All analog and digital peripherals are fully functional while debugging. The on-chip 5V-to-3.3V regulator enables operation from 2.2 V up to a 5.25 V supply. Devices are available in 28-pin QFN, 20-pin QFN, or 24-pin QSOP packages. All package options are lead-free and RoHS compliant.

2. Ordering Information

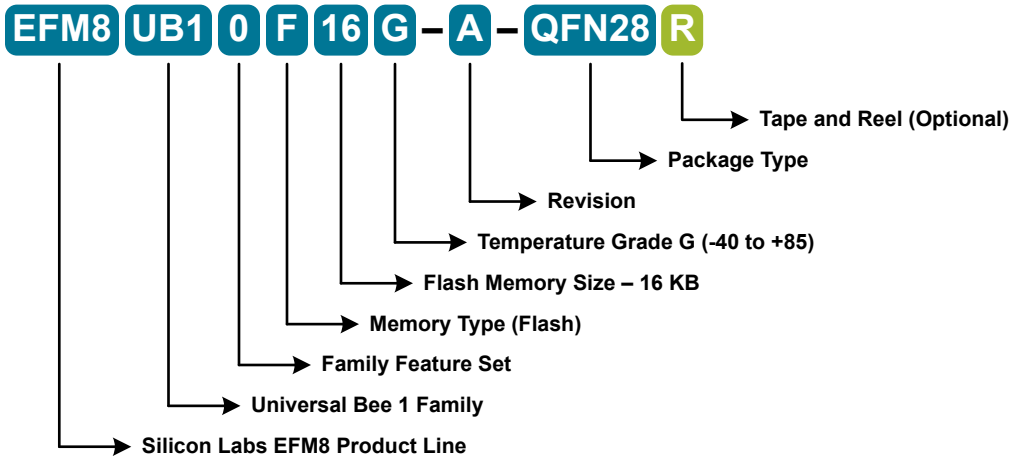

Figure 2.1. EFM8UB1 Part Numbering

All EFM8UB1 family members have the following features:

- CIP-51 Core running up to 50 MHz
- Three Internal Oscillators (48 MHz, 24.5 MHz and 80 kHz)
- USB Full/Low speed Function Controller
- SMBus
- I2C Slave
- SPI
- 2 UARTs
- 3-Channel Programmable Counter Array (PWM, Clock Generation, Capture/Compare)
- 5 16-bit Timers
- 2 Analog Comparators
- 12-bit Analog-to-Digital Converter with integrated multiplexer, voltage reference, and temperature sensor
- 16-bit CRC Unit
- Pre-loaded USB bootloader

In addition to these features, each part number in the EFM8UB1 family has a set of features that vary across the product line. The product selection guide shows the features available on each family member.

Table 2.1. Product Selection Guide

Ordering Part Number	Flash Memory (kB)	RAM (Bytes)	Digital Port I/Os (Total)	ADC0 Channels	Comparator 0 Inputs	Comparator 1 Inputs	Pb-free (RoHS Compliant)	Separate VIO and VDD Pins	Temperature Range	Package
EFM8UB10F16G-C-QFN28	16	2304	22	20	10	12	Yes	—	-40 to +85 °C	QFN28
EFM8UB11F16G-C-QSOP24	16	2304	17	15	8	9	Yes	Yes	-40 to +85 °C	QSOP24
EFM8UB10F16G-C-QFN20	16	2304	13	11	8	5	Yes	—	-40 to +85 °C	QFN20
EFM8UB10F8G-C-QFN20	8	2304	13	11	8	5	Yes	—	-40 to +85 °C	QFN20

3. System Overview

3.1 Introduction

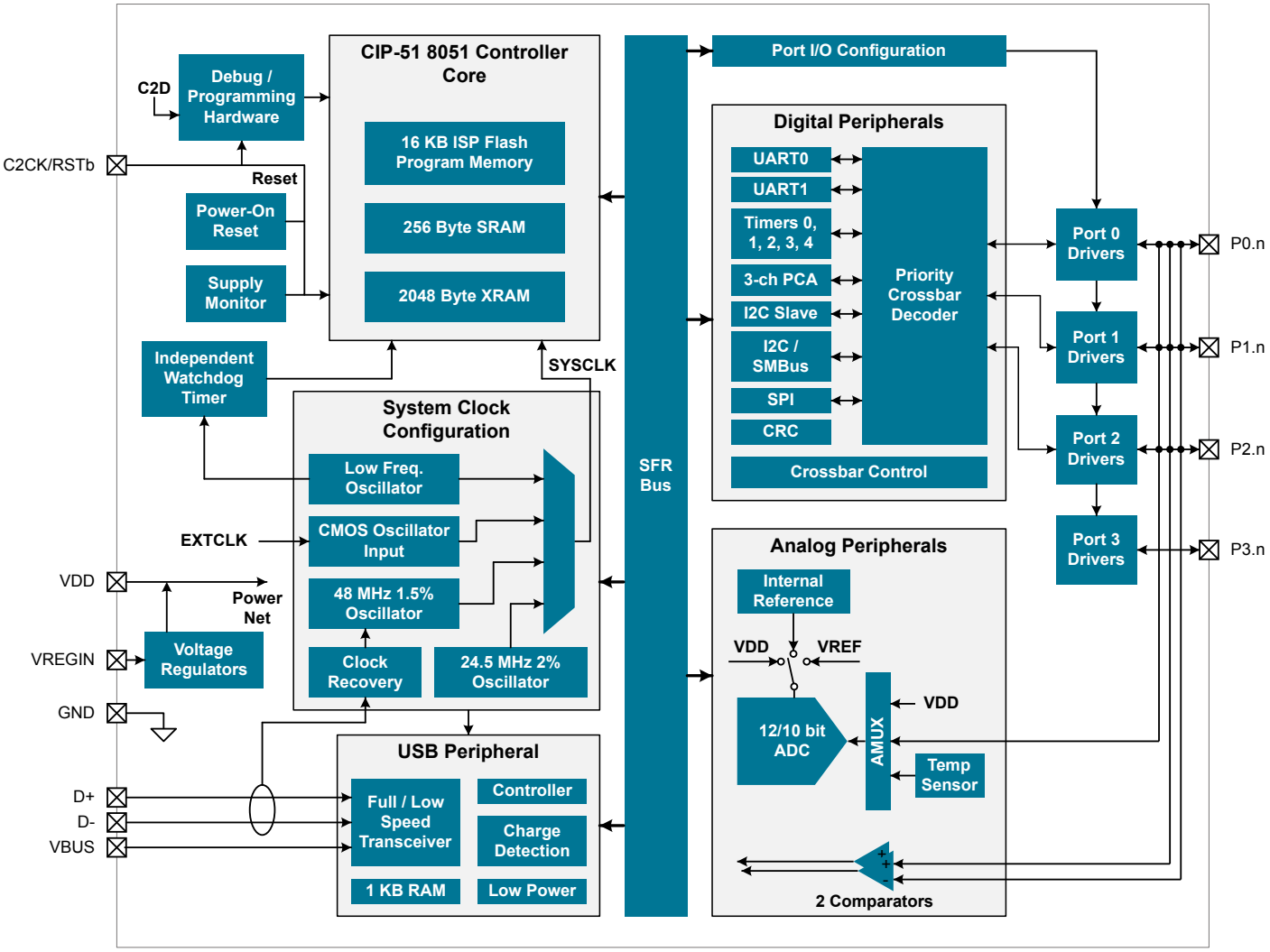

Figure 3.1. Detailed EFM8UB1 Block Diagram

3.2 Power

All internal circuitry draws power from the VDD supply pin. External I/O pins are powered from the VIO supply voltage (or VDD on devices without a separate VIO connection), while most of the internal circuitry is supplied by an on-chip LDO regulator. Control over the device power can be achieved by enabling/disabling individual peripherals as needed. Each analog peripheral can be disabled when not in use and placed in low power mode. Digital peripherals, such as timers and serial buses, have their clocks gated off and draw little power when they are not in use.

Table 3.1. Power Modes

Power Mode	Details	Mode Entry	Wake-Up Sources
Normal	Core and all peripherals clocked and fully operational	—	—
Idle	• Core halted • All peripherals clocked and fully operational • Code resumes execution on wake event	Set IDLE bit in PCON0	Any interrupt
Suspend	• Core and peripheral clocks halted • HFOSC0 and HFOSC1 oscillators stopped • Regulators in normal bias mode for fast wake • Timer 3 and 4 may clock from LFOSC0 • Code resumes execution on wake event	1. Switch SYSCLK to HFOSC0 2. Set SUSPEND bit in PCON1	• USB0 Bus Activity • Timer 4 Event • SPI0 Activity • I2C0 Slave Activity • Port Match Event • Comparator 0 Falling Edge
Stop	• All internal power nets shut down • 5V regulator remains active (if enabled) • Internal 1.8 V LDO on • Pins retain state • Exit on any reset source	1. Clear STOPCF bit in REG0CN 2. Set STOP bit in PCON0	Any reset source
Snooze	• Core and peripheral clocks halted • HFOSC0 and HFOSC1 oscillators stopped • Regulators in low bias current mode for energy savings • Timer 3 and 4 may clock from LFOSC0 • Code resumes execution on wake event	1. Switch SYSCLK to HFOSC0 2. Set SNOOZE bit in PCON1	• USB0 Bus Activity • Timer 4 Event • SPI0 Activity • I2C0 Slave Activity • Port Match Event • Comparator 0 Falling Edge
Shutdown	• All internal power nets shut down • 5V regulator remains active (if enabled) • Internal 1.8 V LDO off to save energy • Pins retain state • Exit on pin or power-on reset	1. Set STOPCF bit in REG0CN 2. Set STOP bit in PCON0	• RSTb pin reset • Power-on reset

3.3 I/O

Digital and analog resources are externally available on the device's multi-purpose I/O pins. Port pins P0.0-P2.3 can be defined as general-purpose I/O (GPIO), assigned to one of the internal digital resources through the crossbar or dedicated channels, or assigned to an analog function. Port pins P3.0 and P3.1 can be used as GPIO. Additionally, the C2 Interface Data signal (C2D) is shared with P3.0.

The port control block offers the following features:

- Up to 22 multi-functions I/O pins, supporting digital and analog functions.
- Flexible priority crossbar decoder for digital peripheral assignment.
- Two drive strength settings for each port.
- Two direct-pin interrupt sources with dedicated interrupt vectors (INT0 and INT1).
- Up to 20 direct-pin interrupt sources with shared interrupt vector (Port Match).

3.10 Bootloader

All devices come pre-programmed with a USB bootloader. This bootloader resides in the code security page and last pages of code flash; it can be erased if it is not needed.

The byte before the Lock Byte is the Bootloader Signature Byte. Setting this byte to a value of 0xA5 indicates the presence of the bootloader in the system. Any other value in this location indicates that the bootloader is not present in flash.

When a bootloader is present, the device will jump to the bootloader vector after any reset, allowing the bootloader to run. The bootloader then determines if the device should stay in bootload mode or jump to the reset vector located at 0x0000. When the bootloader is not present, the device will jump to the reset vector of 0x0000 after any reset.

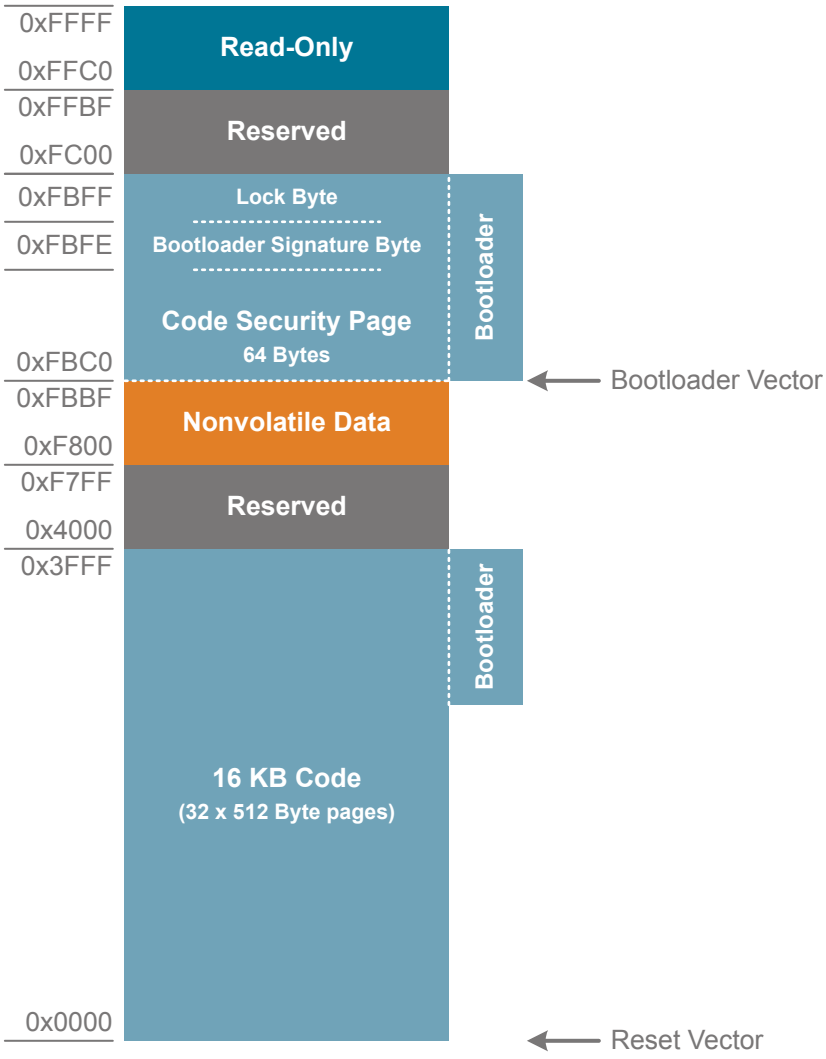

Figure 3.2. Flash Memory Map with Bootloader—16 KB Devices

4. Electrical Specifications

4.1 Electrical Characteristics

All electrical parameters in all tables are specified under the conditions listed in Table 4.1 Recommended Operating Conditions on page 12, unless stated otherwise.

4.1.1 Recommended Operating Conditions

Table 4.1. Recommended Operating Conditions

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Operating Supply Voltage on VDD [1]	V_{DD}		2.2	—	3.6	V
Operating Supply Voltage on VIO [3]	V_{IO}		1.71	—	V_{DD}	V
Operating Supply Voltage on VREGIN	V_{REGIN}		3.0	—	5.25	V
System Clock Frequency	f_{SYSCLK}		0	—	50	MHz
Operating Ambient Temperature	T_A		-40	—	85	°C

Note:

1. Standard USB compliance tests require 3.0 V on VDD for compliant operation.
2. All voltages with respect to GND.
3. On devices without a VIO pin, $V_{IO} = V_{DD}$.
4. GPIO levels are undefined whenever VIO is less than 1 V.

4.1.6 Internal Oscillators

Table 4.6. Internal Oscillators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
High Frequency Oscillator 0 (24.5 MHz)						
Oscillator Frequency	f_{HFOSC0}	Full Temperature and Supply Range	24	24.5	25	MHz
Power Supply Sensitivity	PSS_{HFOSC0}	T_A = 25 °C	—	0.5	—	%/V
Temperature Sensitivity	TS_{HFOSC0}	V_{DD} = 3.0 V	—	40	—	ppm/°C
High Frequency Oscillator 1 (48 MHz)						
Oscillator Frequency	f_{HFOSC1}	Full Temperature and Supply Range	47.3	48	48.7	MHz
Power Supply Sensitivity	PSS_{HFOSC1}	T_A = 25 °C	—	0.02	—	%/V
Temperature Sensitivity	TS_{HFOSC1}	V_{DD} = 3.0 V	—	45	—	ppm/°C
Low Frequency Oscillator (80 kHz)						
Oscillator Frequency	f_{LFOSC}	Full Temperature and Supply Range	75	80	85	kHz
Power Supply Sensitivity	PSS_{LFOSC}	T_A = 25 °C	—	0.05	—	%/V
Temperature Sensitivity	TS_{LFOSC}	V_{DD} = 3.0 V	—	65	—	ppm/°C

4.1.7 External Clock Input

Table 4.7. External Clock Input

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
External Input CMOS Clock Frequency (at EXTCLK pin)	f_{CMOS}		0	—	50	MHz
External Input CMOS Clock High Time	t_{CMOSH}		9	—	—	ns
External Input CMOS Clock Low Time	t_{CMOSL}		9	—	—	ns

4.1.8 ADC

Table 4.8. ADC

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Resolution	N_{bits}	12 Bit Mode		12		Bits
		10 Bit Mode		10		Bits
Throughput Rate (High Speed Mode)	f_S	12 Bit Mode	—	—	200	ksps
		10 Bit Mode	—	—	800	ksps
Throughput Rate (Low Power Mode)	f_S	12 Bit Mode	—	—	62.5	ksps
		10 Bit Mode	—	—	250	ksps
Tracking Time	t_{TRK}	High Speed Mode	230	—	—	ns
		Low Power Mode	450	—	—	ns
Power-On Time	t_{PWR}		1.2	—	—	µs
SAR Clock Frequency	f_{SAR}	High Speed Mode, Reference is 2.4 V internal	—	—	6.25	MHz
		High Speed Mode, Reference is not 2.4 V internal	—	—	12.5	MHz
		Low Power Mode	—	—	4	MHz
Conversion Time	t_{CNV}	10-Bit Conversion, SAR Clock = 12.25 MHz, System Clock = 24.5 MHz.		1.1		µs
Sample/Hold Capacitor	C_{SAR}	Gain = 1	—	5	—	pF
		Gain = 0.5	—	2.5	—	pF
Input Pin Capacitance	C_{IN}		—	20	—	pF
Input Mux Impedance	R_{MUX}		—	550	—	Ω
Voltage Reference Range	V_{REF}		1	—	V_{IO}	V
Input Voltage Range [1]	V_{IN}	Gain = 1	0	—	V_{REF}	V
		Gain = 0.5	0	—	$2xV_{REF}$	V
Power Supply Rejection Ratio	$PSRR_{ADC}$		—	70	—	dB
DC Performance						
Integral Nonlinearity	INL	12 Bit Mode	—	±1	±2.3	LSB
		10 Bit Mode	—	±0.2	±0.6	LSB
Differential Nonlinearity (Guaranteed Monotonic)	DNL	12 Bit Mode	-1	±0.7	1.9	LSB
		10 Bit Mode	—	±0.2	±0.6	LSB
Offset Error	E_{OFF}	12 Bit Mode, VREF = 1.65 V	-3	0	3	LSB
		10 Bit Mode, VREF = 1.65 V	-2	0	2	LSB
Offset Temperature Coefficient	TC_{OFF}		—	0.004	—	LSB/°C

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Slope Error	E_M	12 Bit Mode	—	±0.02	±0.1	%
		10 Bit Mode	—	±0.06	±0.24	%
Dynamic Performance 10 kHz Sine Wave Input 1dB below full scale, Max throughput, using AGND pin						
Signal-to-Noise	SNR	12 Bit Mode	61	66	—	dB
		10 Bit Mode	53	60	—	dB
Signal-to-Noise Plus Distortion	SNDR	12 Bit Mode	61	66	—	dB
		10 Bit Mode	53	60	—	dB
Total Harmonic Distortion (Up to 5th Harmonic)	THD	12 Bit Mode	—	71	—	dB
		10 Bit Mode	—	70	—	dB
Spurious-Free Dynamic Range	SFDR	12 Bit Mode	—	-79	—	dB
		10 Bit Mode	—	-70	—	dB

Note:
1. Absolute input pin voltage is limited by the V_{DD} supply.

4.1.9 Voltage Reference

Table 4.9. Voltage Reference

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Internal Fast Settling Reference						
Output Voltage (Full Temperature and Supply Range)	V_{REFFS}	1.65 V Setting	1.62	1.65	1.68	V
		2.4 V Setting, V_{DD} > 2.6 V	2.35	2.4	2.45	V
Temperature Coefficient	TC_{REFFS}		—	50	—	ppm/°C
Turn-on Time	t_{REFFS}		—	—	1.5	µs
Power Supply Rejection	$PSRR_{REFFS}$		—	400	—	ppm/V
External Reference						
Input Current	I_{EXTREF}	Sample Rate = 800 ksps; VREF = 3.0 V	—	8	—	µA

4.1.10 Temperature Sensor

Table 4.10. Temperature Sensor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Offset	V_{OFF}	T_A = 0 °C	—	757	—	mV
Offset Error [1]	E_{OFF}	T_A = 0 °C	—	17	—	mV
Slope	M		—	2.85	—	mV/°C
Slope Error [1]	E_M		—	70	—	µV/°
Linearity			—	0.5	—	°C
Turn-on Time			—	1.8	—	µs

Note:
1. Represents one standard deviation from the mean.

4.1.11 5 V Voltage Regulator

Table 4.11. 5V Voltage Regulator

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Input Voltage Range [1]	V_{REGIN}		3.0	—	5.25	V
Output Voltage on VDD [2]	V_{REGOUT}	Output Current = 1 to 100 mA Regulation range (VREGIN ≥ 4.1V)	3.1	3.3	3.6	V
		Output Current = 1 to 100 mA Dropout range (VREGIN < 4.1V)	—	V_{REGIN} – $V_{DROPOUT}$	—	V
Output Current [2]	I_{REGOUT}		—	—	100	mA
Dropout Voltage	$V_{DROPOUT}$	Output Current = 100 mA	—	—	0.8	V

Note:
1. Input range to meet the Output Voltage on VDD specification. If the 5 V voltage regulator is not used, VREGIN should be tied to VDD.
2. Output current is total regulator output, including any current required by the device.

4.1.14 USB Transceiver

Table 4.14. USB Transceiver

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Transmitter						
Output High Voltage	V_{OH}	V_{DD} ≥3.0V	2.8	—	—	V
Output Low Voltage	V_{OL}	V_{DD} ≥3.0V	—	—	0.8	V
Output Crossover Point	V_{CRS}		1.3	—	2.0	V
Output Impedance	Z_{DRV}	Driving High	28	36	44	Ω
		Driving Low	28	36	44	
Pull-up Resistance	R_{PU}	Full Speed (D+ Pull-up)	1.425	1.5	1.575	kΩ
		Low Speed (D- Pull-up)				
Output Rise Time	T_R	Low Speed	75	—	300	ns
		Full Speed	4	—	20	ns
Output Fall Time	T_F	Low Speed	75	—	300	ns
		Full Speed	4	—	20	ns
Receiver						
Differential Input Sensitivity	V_{DI}	| (D+) - (D-) |	0.2	—	—	V
Differential Input Common Mode Range	V_{CM}		0.8	—	2.5	V
Input Leakage Current	I_L	Pullups Disabled	—	<1.0	—	µA
Refer to the USB Specification for timing diagrams and symbol definitions.						

4.2 Thermal Conditions

Table 4.15. Thermal Conditions

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Thermal Resistance	θ_{JA}	QFN-20 Packages	—	60	—	°C/W
		QFN-28 Packages	—	26	—	°C/W
		QSOP-24 Packages	—	65	—	°C/W

Note:
1. Thermal resistance assumes a multi-layer PCB with any exposed pad soldered to a PCB pad.

5. Typical Connection Diagrams

5.1 Power

The figure below shows a typical connection diagram for the power pins of the EFM8UB1 devices when the internal regulator used and USB is connected (bus-powered). VBUS is not used as a sense pin in this scenario, so that pin can be used as a standard GPIO.

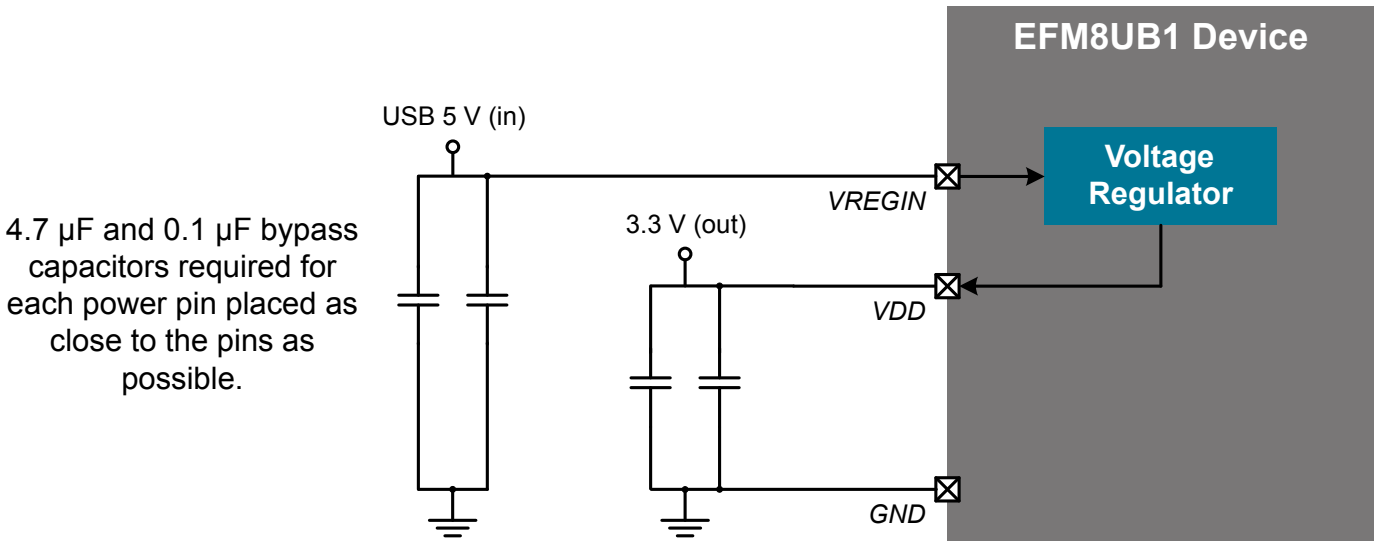

Figure 5.1. Connection Diagram with Voltage Regulator Used and USB Connected (Bus-Powered)

The figure below shows a typical connection diagram for the power pins of the EFM8UB1 devices when the internal regulator used and USB is connected (self-powered). The VBUS signal is used to detect when USB is connected to a host device.

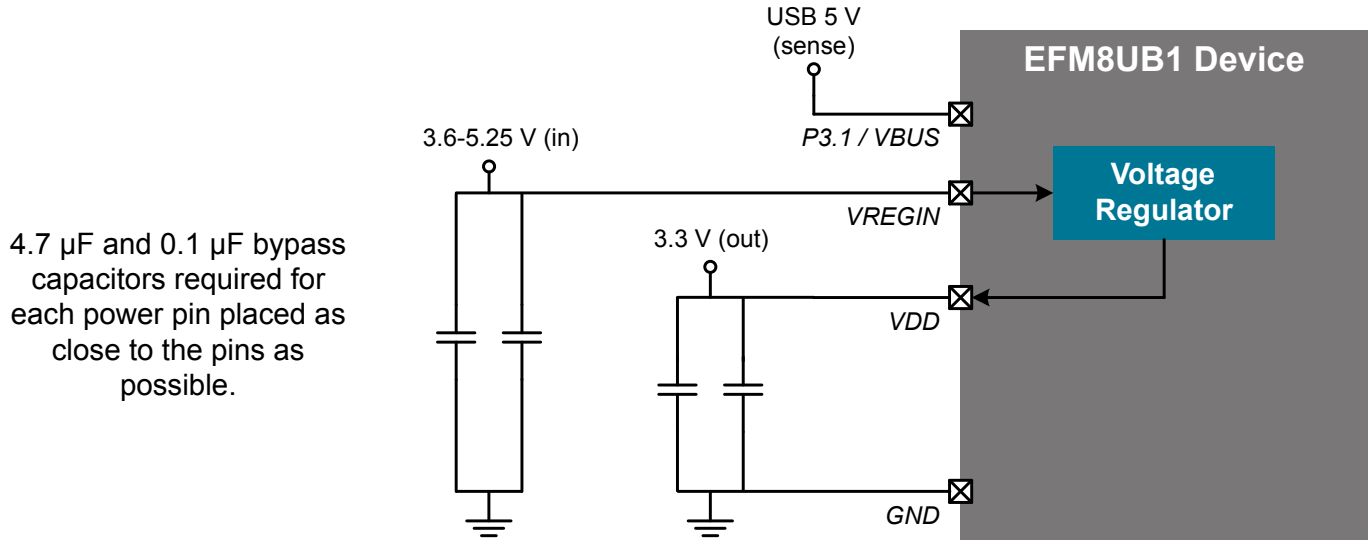

Figure 5.2. Connection Diagram with Voltage Regulator Used and USB Connected (Self-Powered)

The figure below shows a typical connection diagram for the power pins of the EFM8UB1 devices when the internal 5 V-to-3.3 V regulator is not used.

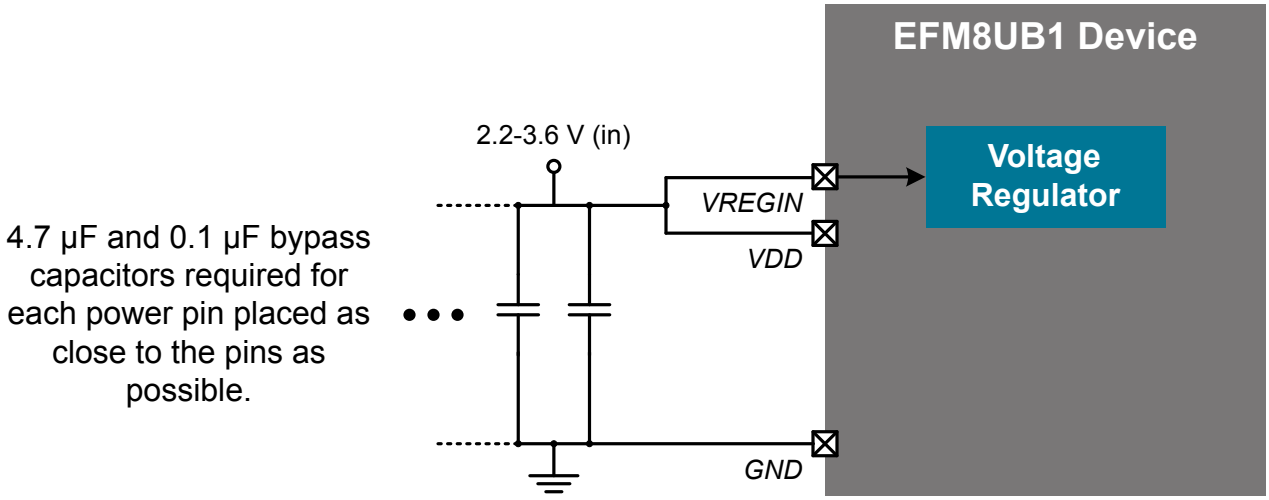

Figure 5.3. Connection Diagram with Voltage Regulator Not Used

6.2 EFM8UB1x-QSOP24 Pin Definitions

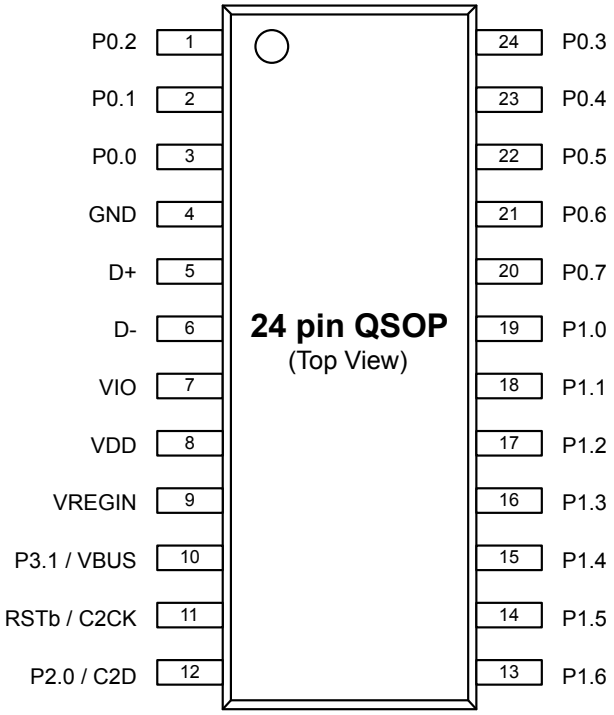

Figure 6.2. EFM8UB1x-QSOP24 Pinout

Table 6.2. Pin Definitions for EFM8UB1x-QSOP24

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.2	Multifunction I/O	Yes	P0MAT.2 INT0.2 INT1.2	ADC0.2 CMP0P.2 CMP0N.2
2	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1	ADC0.1 CMP0P.1 CMP0N.1 AGND

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
3	GND	Ground			
4	D+	USB Data Positive			ADC0.28
5	D-	USB Data Negative			ADC0.29
6	VDD	Supply Power Input / 5V Regulator Output			
7	VREGIN	5V Regulator Input			
8	P3.1	Multifunction I/O		VBUS	
9	RST / C2CK	Active-low Reset / C2 Debug Clock			
10	P2.0 / C2D	Multifunction I/O / C2 Debug Data	Yes		
11	P1.2	Multifunction I/O	Yes	P1MAT.2 I2C0_SCL	ADC0.10 CMP1P.4 CMP1N.4
12	GND	Ground			
13	P1.1	Multifunction I/O	Yes	P1MAT.1 I2C0_SDA	ADC0.9 CMP1P.3 CMP1N.3
14	P1.0	Multifunction I/O	Yes	P1MAT.0	ADC0.8 CMP1P.2 CMP1N.2
15	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7	ADC0.7 CMP1P.1 CMP1N.1 CMP0P.7 CMP0N.7
16	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6	ADC0.6 CMP1P.0 CMP1N.0 CMP0P.6 CMP0N.6
17	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5 UART0_RX	ADC0.5 CMP0P.5 CMP0N.5

7.2 QFN28 PCB Land Pattern

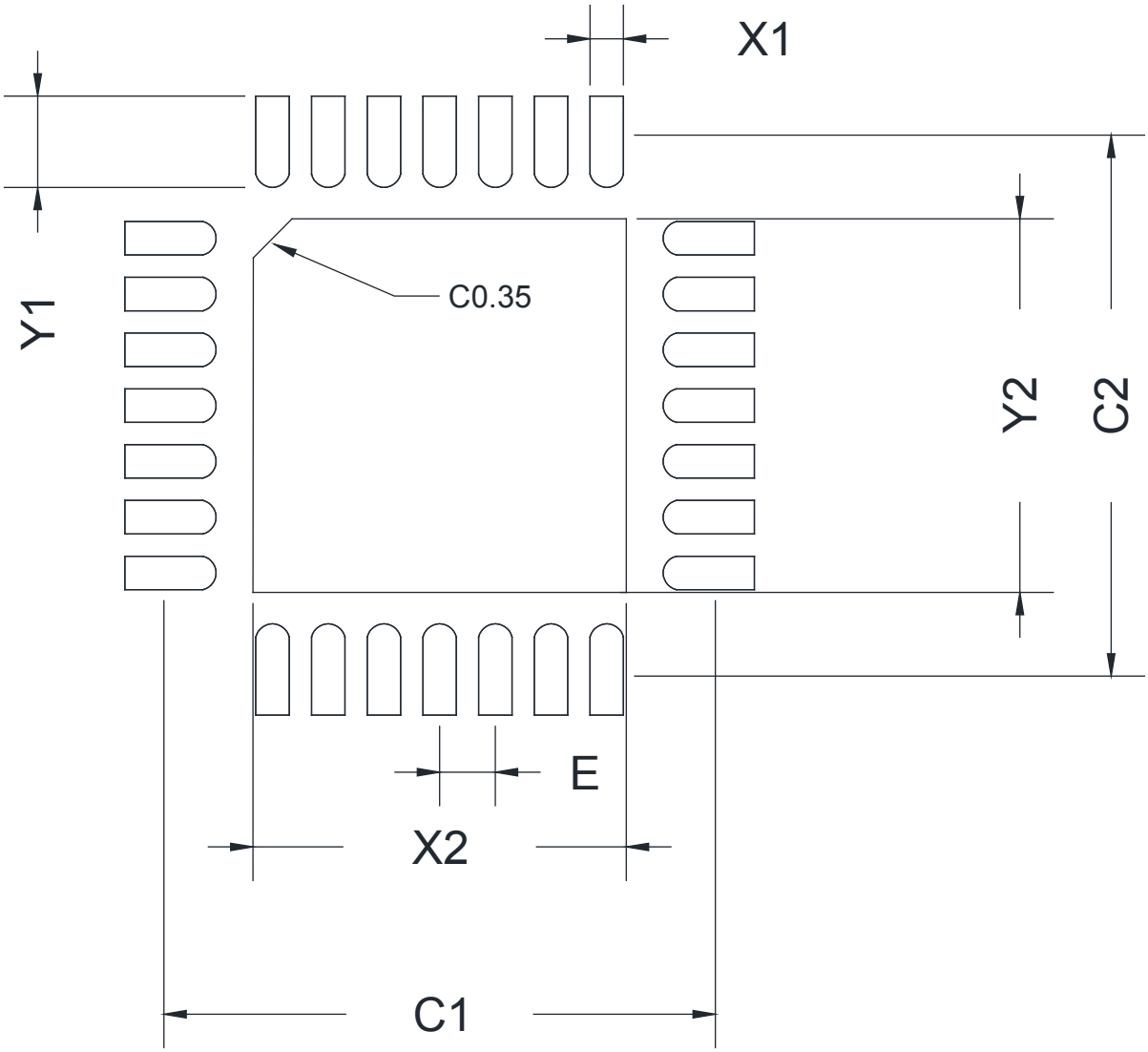

Figure 7.2. QFN28 PCB Land Pattern Drawing

Table 7.2. QFN28 PCB Land Pattern Dimensions

Dimension	Min	Max
C1	4.80	
C2	4.80	
E	0.50	
X1	0.30	
X2	3.35	
Y1	0.95	

Dimension	Min	Typ	Max
aaa		0.20	
bbb		0.18	
ccc		0.10	
ddd		0.10	

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC outline MO-137, variation AE.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

Dimension	Min	Typ	Max
E		3.00 BSC	
E2	1.60	1.70	1.80
f		2.50 BSC	
L	0.30	0.40	0.50
K		0.25 REF	
R	0.09	0.125	0.15
aaa		0.15	
bbb		0.10	
ccc		0.10	
ddd		0.05	
eee		0.08	
fff		0.10	

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. The drawing complies with JEDEC MO-220.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

9.2 QFN20 PCB Land Pattern

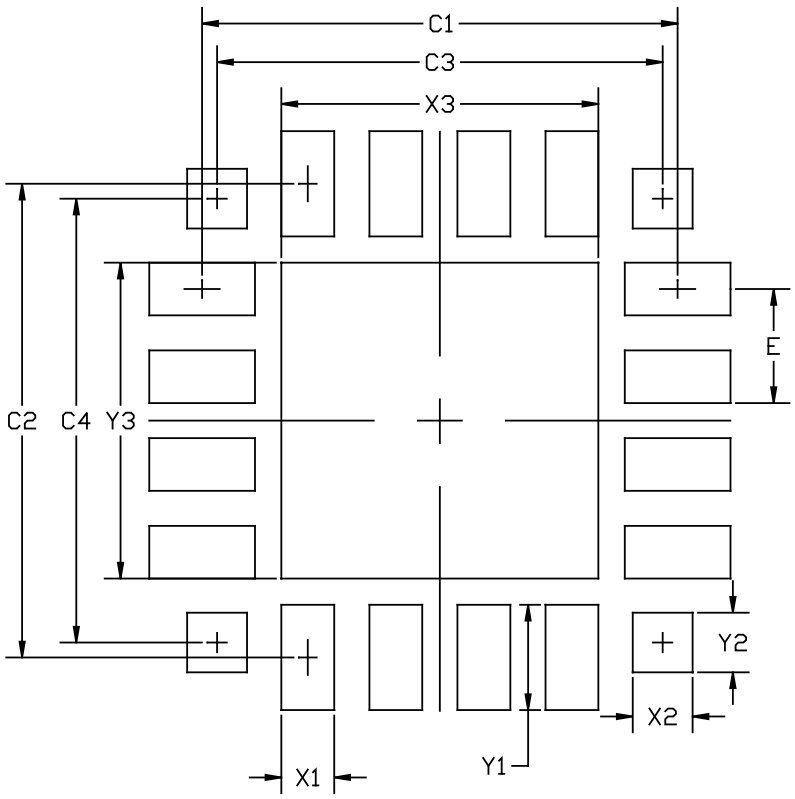

Figure 9.2. QFN20 PCB Land Pattern Drawing

Table 9.2. QFN20 PCB Land Pattern Dimensions

Dimension	Min	Max
C1	3.10	
C2	3.10	
C3	2.50	
C4	2.50	
E	0.50	
X1	0.30	
X2	0.25	0.35
X3	1.80	
Y1	0.90	
Y2	0.25	0.35
Y3	1.80	

Dimension	Min	Max

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification.
3. This Land Pattern Design is based on the IPC-7351 guidelines.
4. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.
5. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
6. The stencil thickness should be 0.125 mm (5 mils).
7. The ratio of stencil aperture to land pad size should be 1:1 for the perimeter pads.
8. A 2 x 2 array of 0.75 mm openings on a 0.95 mm pitch should be used for the center pad to assure proper paste volume.
9. A No-Clean, Type-3 solder paste is recommended.
10. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

9.3 QFN20 Package Marking

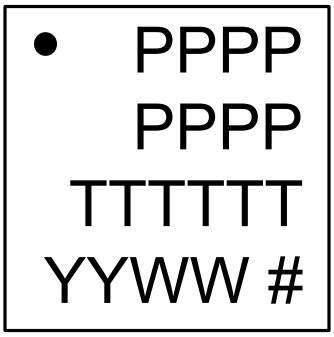

Figure 9.3. QFN20 Package Marking

The package marking consists of:

- PPPPPPPP – The part number designation.
- TTTTTT – A trace or manufacturing code.
- YY – The last 2 digits of the assembly year.
- WW – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).